

# FGP90N30

## 300V, 90A PDP IGBT

### Features

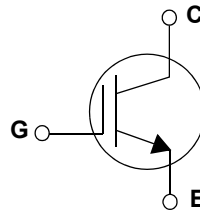
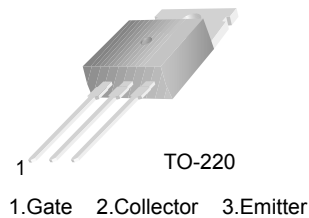
- High Current Capability
- Low saturation voltage :  $V_{CE(sat)} = 1.1\text{ V @ } I_C = 20\text{ A}$
- High input impedance
- Fast switching

### General Description

Employing Unified IGBT Technology, Fairchild's PDP IGBTs provides low conduction and switching loss. The PWD series offers the optimum solution for PDP applications where low - conduction loss is essential.

### Application

- . PDP System



### Absolute Maximum Ratings

Symbol	Description	FGP90N30	Units
$V_{CES}$	Collector-Emitter Voltage	300	V
$V_{GES}$	Gate-Emitter Voltage	$\pm 20$	V
$I_C$	Collector Current @ $T_C = 25^\circ\text{C}$	90	A
$I_{C\_pulse(1)}$	Pulse Collector Current @ $T_C = 25^\circ\text{C}$	130	A
$P_D$	Maximum Power Dissipation @ $T_C = 25^\circ\text{C}$	192	W
	Maximum Power Dissipation @ $T_C = 100^\circ\text{C}$	77	W
$T_J$	Operating Junction Temperature	-55 to +150	$^\circ\text{C}$
$T_{stg}$	Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

### Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$ (IGBT)	Thermal Resistance, Junction-to-Case	--	0.65	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	--	62.5	$^\circ\text{C/W}$

### Notes

- (1) Repetitive test , pulse width=100usec , Duty=0.5

## Package Marking and Ordering Information

Device Marking	Device	Package	Packaging Type	Qty per Tube	Max Qty per Box
FGP90N30	FGP90N30TU	TO-220	Rail / Tube	50ea	-

## Electrical Characteristics T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
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### Off Characteristics

BV <sub>CES</sub>	Collector-Emitter Breakdown Voltage	V <sub>GE</sub> = 0V, I <sub>C</sub> = 250uA	300	--	--	V
ΔBV <sub>CES</sub> /ΔT <sub>J</sub>	Temperature Coefficient of Breakdown Voltage	V <sub>GE</sub> = 0V, I <sub>C</sub> = 250uA	--	0.6	--	V/°C
I <sub>CES</sub>	Collector Cut-Off Current	V <sub>CE</sub> = V <sub>CES</sub> , V <sub>GE</sub> = 0V	--	--	100	uA
I <sub>GES</sub>	G-E Leakage Current	V <sub>GE</sub> = V <sub>GES</sub> , V <sub>CE</sub> = 0V	--	--	± 250	nA

### On Characteristics

V <sub>GE(th)</sub>	G-E Threshold Voltage	I <sub>C</sub> = 250uA, V <sub>CE</sub> = V <sub>GE</sub>	2.5	4.0	5.0	V
V <sub>CE(sat)</sub>	Collector to Emitter Saturation Voltage	I <sub>C</sub> = 20A, V <sub>GE</sub> = 15V	--	1.1	1.4	V
		I <sub>C</sub> = 90 A, V <sub>GE</sub> = 15V T <sub>C</sub> = 25°C	--	1.9	--	V
		I <sub>C</sub> = 90 A, V <sub>GE</sub> = 15V T <sub>C</sub> = 125°C	--	2.0	--	V

### Dynamic Characteristics

C <sub>ies</sub>	Input Capacitance	V <sub>CE</sub> = 30V, V <sub>GE</sub> = 0V, f = 1MHz	--	1700	--	pF
C <sub>oes</sub>	Output Capacitance		--	290	--	pF
C <sub>res</sub>	Reverse Transfer Capacitance		--	80	--	pF

### Switching Characteristics

t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>CC</sub> = 200 V, I <sub>C</sub> = 20A, R <sub>G</sub> = 10Ω, V <sub>GE</sub> = 15V, Resistive Load, T <sub>C</sub> = 25°C	--	30	--	ns
t <sub>r</sub>	Rise Time		--	150	--	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		--	110	--	ns
t <sub>f</sub>	Fall Time		--	140	350	ns
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>CC</sub> = 200 V, I <sub>C</sub> = 20 A, R <sub>G</sub> = 10Ω, V <sub>GE</sub> = 15V, Resistive Load, T <sub>C</sub> = 125°C	--	30	--	ns
t <sub>r</sub>	Rise Time		--	150	--	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		--	110	--	ns
t <sub>f</sub>	Fall Time		--	330	--	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>CE</sub> = 200 V, I <sub>C</sub> = 20A, V <sub>GE</sub> = 15V	--	87	130	nC
Q <sub>ge</sub>	Gate-Emitter Charge		--	12	18	nC
Q <sub>gc</sub>	Gate-Collector Charge		--	38	57	nC

## Typical Performance Characteristics

Figure 1. Typical Output Characteristics

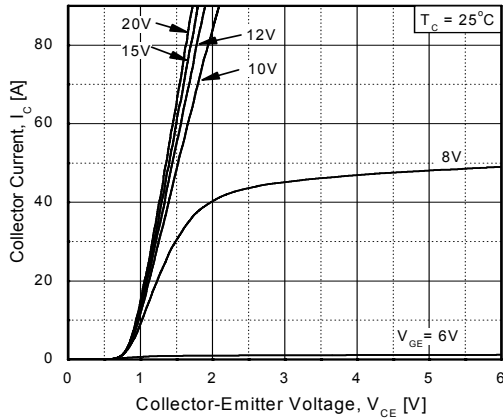


Figure 2. Typical Output Characteristics

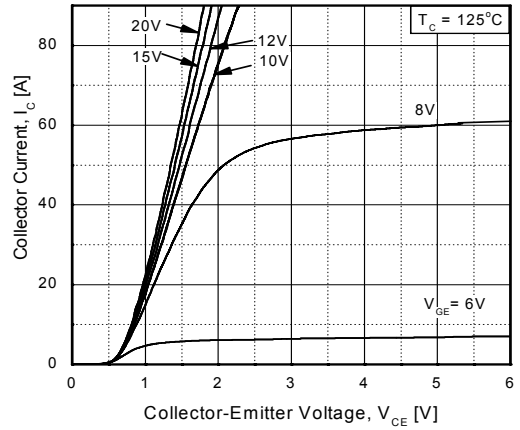


Figure 3 Typical Saturation Voltage Characteristics

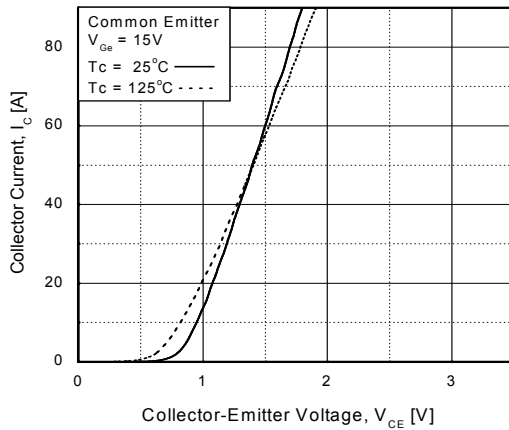


Figure 4. Transfer Characteristics

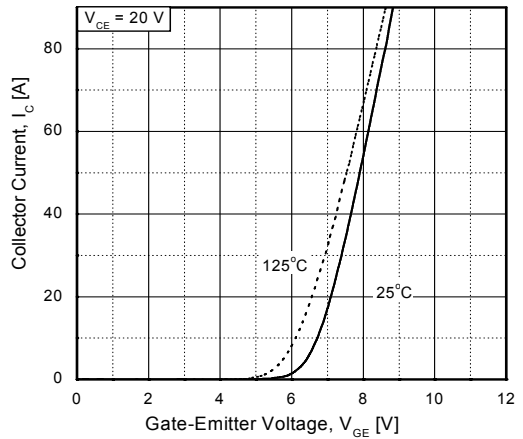


Figure 5. Saturation Voltage vs Case Temperature at Variant Current Level

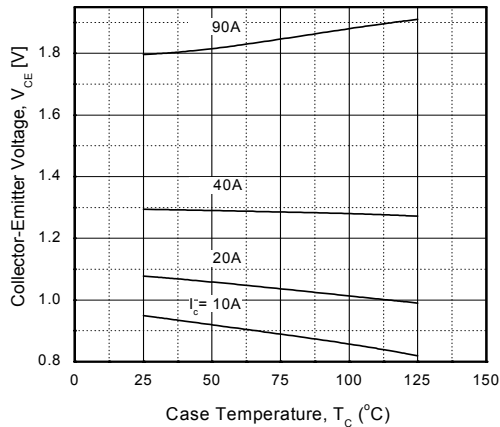


Figure 6. Saturation Voltage vs. Vge

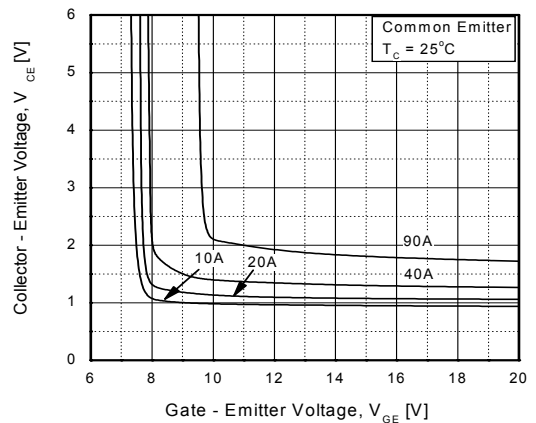


Figure 7. Saturation Voltage vs. V<sub>GE</sub>

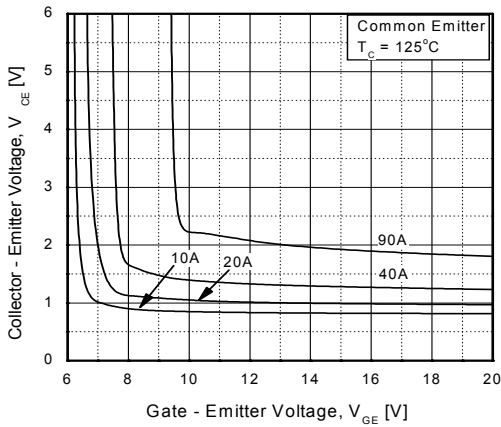


Figure 8. Capacitance Characteristics

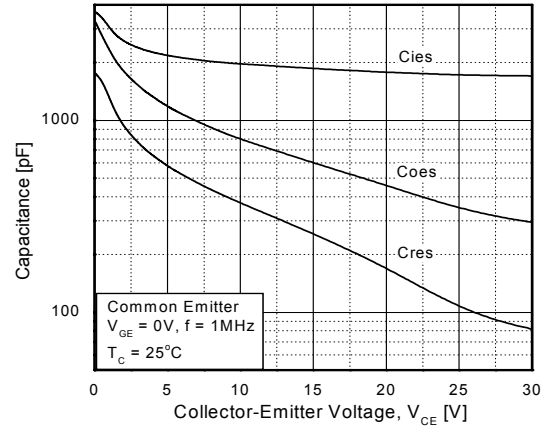


Figure 9. Gate Charge

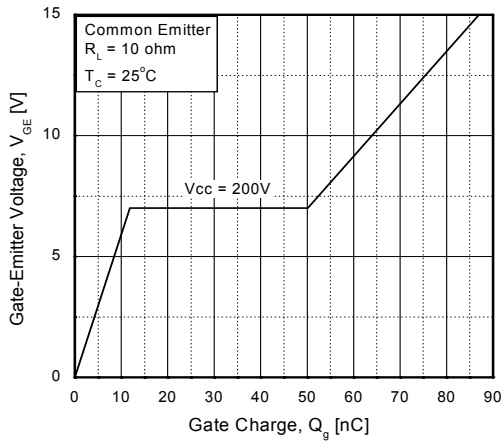


Figure 10. SOA Characteristics

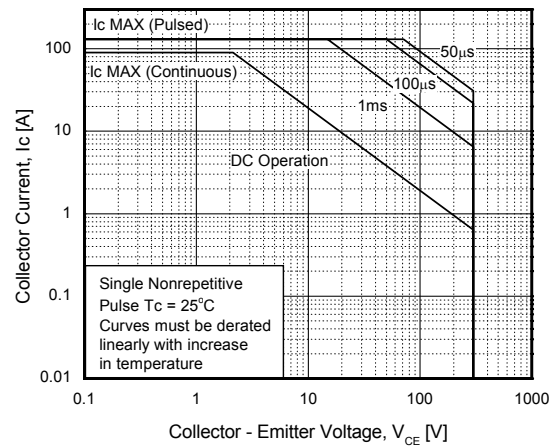


Figure 11. Turn-On Characteristics vs. Gate Resistance

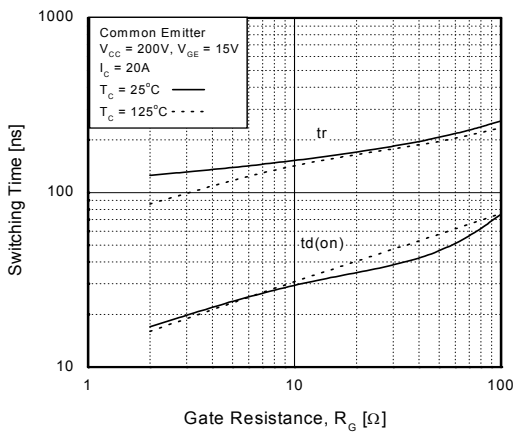


Figure 12. Turn-Off Characteristics vs. Gate Resistance

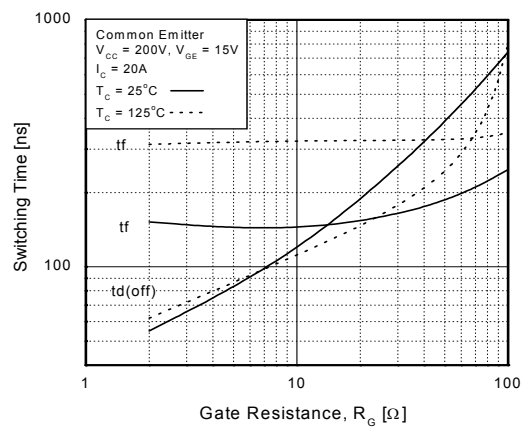


Figure 13 Turn-On Characteristics vs. Collector Current

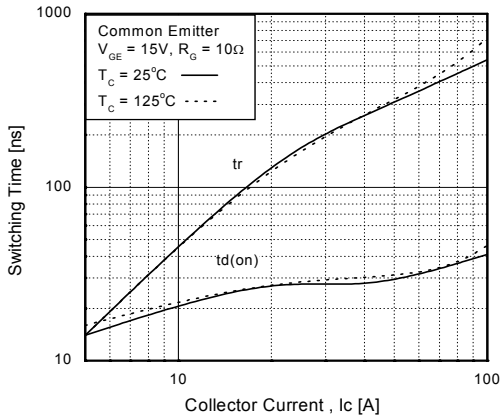


Figure 14. Turn-Off Characteristics vs. Collector Current

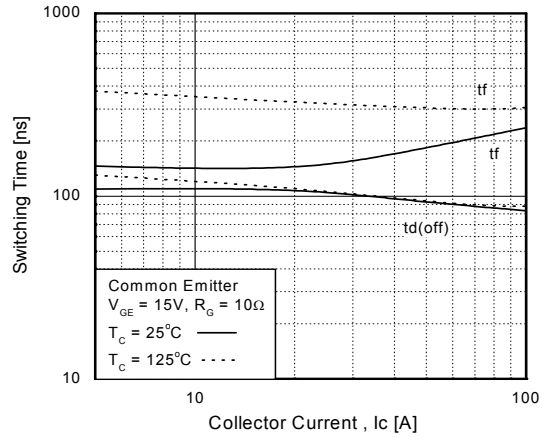


Figure 15. Switching Loss vs. Gate Resistance

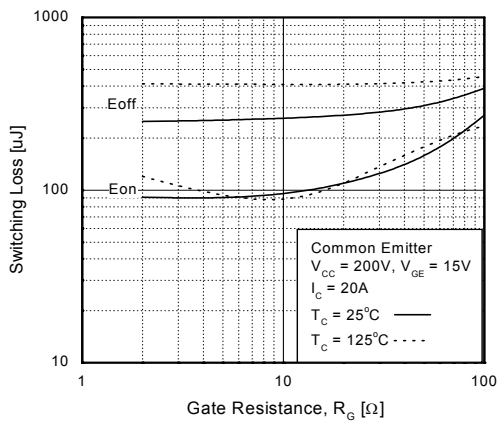


Figure 16. Switching Loss vs. Collector Current

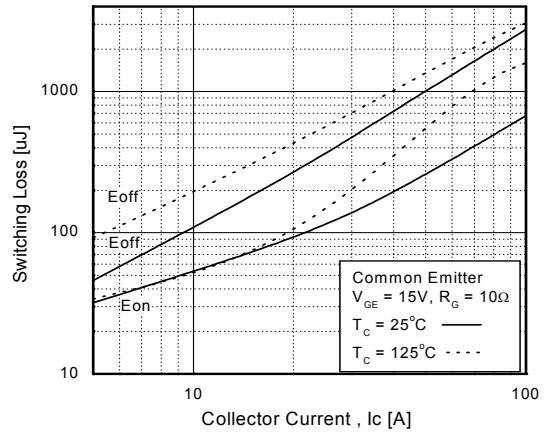
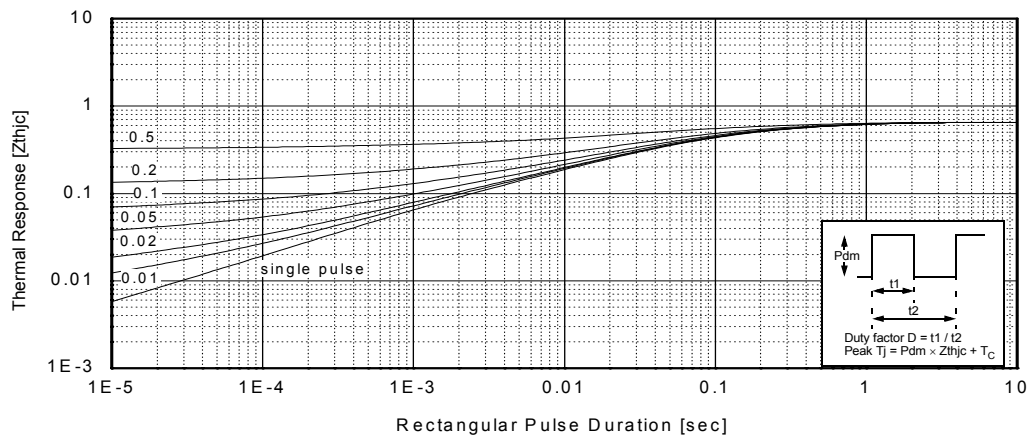
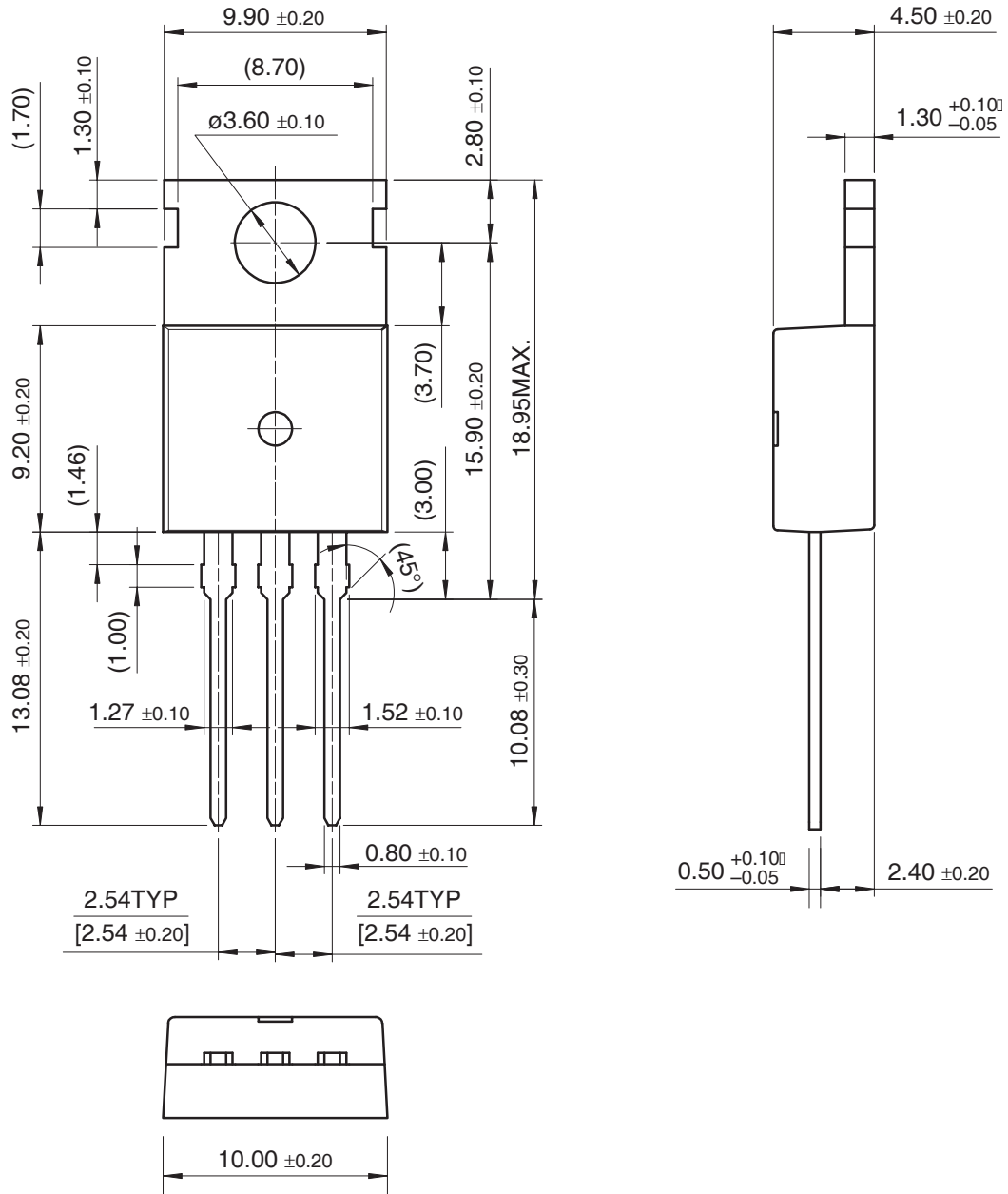


Figure 17. Transient Thermal Impedance of IGBT



Mechanical Dimensions

TO-220



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Rev. 117